



2829

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Bruce et al. Examiner: Chan, E.
Serial No.: 09/915,883 Group Art Unit: 2829
Filed: July 26, 2001 Docket No.: AMDA.508PA
Title: INTEGRATED CIRCUIT DEFECT ANALYSIS USING LIQUID CRYSTAL

6/12
S. Mackey
2-13-03

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence and the papers, as described hereinabove, are being deposited in the United States Postal Service, as first class mail, in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231, on February 4, 2003.

By: Erin M. Nichols
Erin M. Nichols

OFFICE ACTION RESPONSE AND AMENDMENT

Assistant Commissioner for Patents
Washington, D.C. 20231

Dear Sir:

In response to the Office Action dated November 14, 2002, please consider the following amendment and remarks.

In the Claims

Please replace claims 15 and 17 as indicated below. The changes to the claims may be found on the attached sheet.

a1
15. (Amended) The method of claim 14, wherein using the nIR laser light to image the liquid crystal includes evaluating a plurality of images of the liquid crystal.

a2
17. (Amended) The method of claim 1, further comprising removing sufficient amount of substrate from the die for heat transfer from the circuitry to the liquid crystal in a manner that causes a portion of the liquid crystal to reach a temperature near its threshold temperature for changing phase, wherein the liquid crystal is formed over the die after the substrate removal.

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